

SPC-150NX

TCSPC / FLIM Module

Time-Correlated Single Photon Counting Module for Ultra-Fast Detectors

High-resolution version of SPC-150N TCSPC module Improved resolution for ultra-fast detectors Internal timing jitter 1.6 ps rms (3.5 ps fwhm) Minimum time channel width 407 fs Input discriminator bandwidth 4 GHz Sub-ps low-frequency timing wobble Photon distribution and parameter-tag modes Multi-detector / multi-wavelength capability **FLIM** by bh Megapixel Technology

Mosaic FLIM mode

Multiscaler imaging mode

Parallel operation of 2, 3 or 4 modules

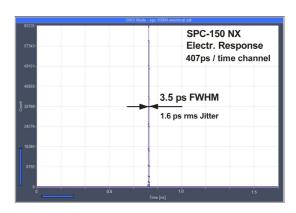
Reversed start/stop: Laser repetition rates up to 150 MHz

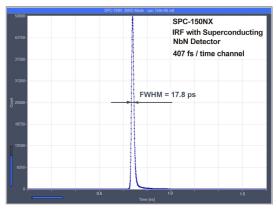
Dead time 100 ns

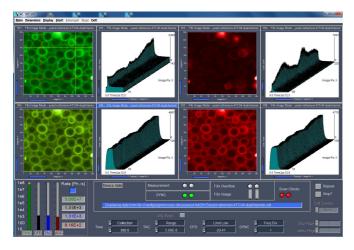
Saturated count rate 10 MHz

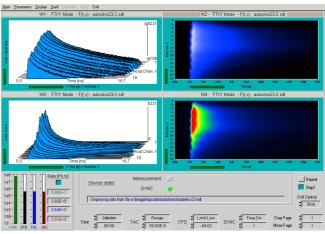
Ultra-fast fluorescence lifetime experiments **Anti-bunching experiments** Multi-wavelength lifetime experiments Recording of transient fluorescence lifetime effects Single-wavelength FLIM, multi-wavelength FLIM Fast-acquisition FLIM, time-series FLIM Mosaic FLIM, lateral, longitudinal, temporal mosaics Simultaneous PLIM and FLIM **Double-exponential FRET imaging**

Recording of Ca²⁺ transients **fNIRS** and NIRS experiments Single-molecule spectroscopy FCS, FCCS, PCH











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More than 20 years experience in multi-dimensional TCSPC. More than 1500 TCSPC systems worldwide.



SPC-150N

TCSPC / FLIM Module

Photon Channel

Principle
Discriminator Input Bandwidth
Time Resolution (FWHM / RMS, electr.)
Variance in time of IRF maximum
Optimum Input Voltage Range
Min. Input Pulse Width
Threshold
Zero Cross Adjust

Synchronisation Channels

Principle
Discriminator Input Bandwidth
Optimal Input Voltage Range
Min. Input Pulse Width
Threshold
Frequency Range
SYNC Frequency Divider
Zero Cross Adjust

Time-to-Amplitude Converters / ADCs

Principle
TAC Range
Biased Amplifier Gain
Biased Amplifier Offset
Time Range incl. Biased Amplifier
min. Time / Channel
ADC Principle
Diff. Nonlinearity, electrical

Data Acquisition (Histogram Modes)

Method
Dead Time
Saturated Count Rate
Useful count rate
max. Counts / Time Channel (counting depth)
Overflow Control
Collection Time
Display Interval Time
Repeat Time
Sequential Recording
Synchronisation with Scanning
Routing
Experiment Trigger

Data Acquisition (FIFO / Parameter-Tag Mode)

Method
Online display
FCS calculation
Number of counts of decay / waveform recording
Dead Time
Saturated count rate, peak
Sustained count rate (bus-transfer limited)
max. counts / time cChannel (counting depth)
Output Data Format (ADC / Macrotime / Routing)
FIFO buffer Capacity (photons)
Macro Timer Resolution, internal clock
Macro Timer Resolution, clock from SYNC input
Routing
External event markers
Experiment trigger

Data Acquisition, FIFO / Parameter-Tag Imaging Mode

Online display Synchronisation with scanner Detector / Wavelength Channels Image resolution, 64-bit SPCM software No of time channels No. of pixels, 1 detector channel No. of pixels, 16 detector channels

Operation Environment

Computer System
Bus Connectors
Used PCI Slots
Total power Consumption
Dimensions

Related Products

SPC-150N TCSPC modules
Simple-Tau 150 compact TCSPC systems
Simple-Tau 154 compact 4-channel TCSPC systems
DCS-120 confocal scanning FLIM system

Constant Fraction Discriminator (CFD)
4 GHz
3.3 ps / 1.6 ps
<1 ps over 50 seconds
- 30 mV to - 500 mV
200 ps
0 to - 250 mV
- 100 mV to + 100 mV

Constant Fraction Discriminator (CFD)
4 GHz
- 30 mV to - 500 mV
200 ps
0 to -250 mV
0 to 150 MHz
1 - 2 - 4
-100 mV to + 100 mV

Ramp Generator / Biased Amplifier
25 ns to 2.5 us
1 to 15
0 to 50% of TAC Range
1.67 ns to 2.5 us
407 fs
50 ns Flash ADC with Error Correction
< 0.5% rms, typ. - 1% peak-peak

on-board multi-dimensional hardware histogramming process 100 ns, independent of computer speed 10 MHz 5 MHz 2 16-1 none / stop / repeat and correct

0.1 us to 100,000 s 0.1 us to 100,000 s 0.1 us to 100,000 s

Programmable Hardware Sequencer, unlimited recording by memory swapping, in curve mode and scan mode pixel, line and frame clocks from scanning device

7 bit TTL TTL

Parameter-tagging of individual photons and continuous writing to disk Decay function, FCS, Cross-FCS, PCH, MCS traces Multi-tau algorithm, online calculation and online fit unlimited

unlimited 100 ns 10 MHz typ. 4 MHz unlimited 12 / 12 / 4 bit 2-10⁶

50 ns, 12 bit, overflows marked by MTOF entry in data stream 10 ns to 100 ns, 12 bit, overflows marked by MTOF entry in data stream

4 bit TTL 4 bit, TTL TTI

Buildup of images from time- and wavelength tagged data up to 8 images in different time and wavelength windows via Frame Clock, Line Clock, and Pixel Clock pulses 1 to 16

64 256 1024 4096 4096 x 4096 2048 x 2048 1024 x 1024 512 x 512 1024 x 1024 512 x 512 256 x 256 128 x 128

PC Pentium, multi-core, >8GB RAM and 64 bit operating system recommended PCI

1 approx. 12 W from +5V, 0.7 W from +12V 240 mm x 130 mm x 15 mm

HPM-100 GaAsP and GaAs hybrid detectors PML-SPEC and MW-FLIM multi-wavelength detectors PMC-100 cooled PMT modules id-100 SPAD detector modules

DCC-100 detector controller BDL-SMN ps diode lasers BDS-SM, -SMY, -MM picosecond diode lasers

Related Literature

World Record in TCSPC Time Resolution: Combination of bh SPC-150NX with SCONTEL NbN Detector yields 17.8 ps FWHM. Application note, please see www.becker-hickl.com W. Becker, Advanced time-correlated single photon counting techniques. Springer 2005. Please contact bh for availability.

W. Becker, The bh TCSPC Handbook, 6th edition (2015). Available on www.becker-hickl.com. Contact bh for printed copies.

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